List of Acronyms

ASIC - Application Specific Integrated Circuit
AT - ASIC Tester
ATPG - Automatic Test Pattern Generation
ATE - Automatic Test Equipment
BEE - Berkeley Emulation Engine
BIST - Built-In Self-Test
CAD - Computer-Aided Design.
CDM - Command Decoder Module
CMOS - Complementary Metal-Oxide Semiconductor.
CPU - Central Processing Unit.
CPLD - Complex Programmable Logic Device
CUT - Circuit Under Test
DCM - Data Control Module
DFT - Design for Testability.
DUT - Device Under Test
DSM - Deep Sub-Micron
EDA - Electronic Design Automation.
EFP - Essential Fault Pruning
EFR - Essential Fault Reduction
FEM - Function Encoder Module
FIFO - First In First Out
FPGA - Field Programmable Gate Array.
FSM - Finite State Machine.
HCFG - Hierarchical Concurrent Flow Graph
List of Acronyms

ASIC - Application Specific Integrated Circuit
ASSP - Application Specific Standard Products
AT – ASIC Tester
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FPGA - Field Programmable Gate Array.
FSM - Finite State Machine.
HCFG - Hierarchical Concurrent Flow Graph
HW - Hardware
HWE - Hardware Emulators
IAT - In-application Testing
IC - Integrated Circuit.
ILA - Iterative Logic Array
IOC - Input Output Configuration
IP - Intellectual Property
IDM - Input Data Module
IEM - Input Enable Module
ILA - Iterative Logic Array
ITRS - International Technology Roadmap for semiconductors
LFSR - Linear Feedback Shift Register
MLM - Master Logger Module
MOS - Metal-Oxide Semiconductor.
MTFTG - Multiple Target Fault Test Generation
NRE - Non-Recurring Engineering
NTM - Num Timestamps Module
ODM - Output Data Module
OTP - One Time Programmable
PCB - Printed Circuit Board
PRBS - Pseudo-Random Binary Sequence
PI - Primary Inputs
PPI - Pseudo Primary Inputs
PO - Primary Outputs
PPO - Pseudo Primary Outputs
POS - Product of Sums.

ROFS - Reverse Order Fault Simulation

ROM - Read Only Memory.

RTL - Register Transfer Level.

SAT - Boolean Satisfiability

SIE - Serial Interface Engine

SoC - System on Chip

SP3 - Spartan III

SSF - Single Stuck-at Fault

SSI - Small Scale Integration

STM - Start Test Module

SW - Software

TVM - Test Vector Memory

TPG - Test Pattern Generator

TOS - Time of Start

TMR - Triple Modular Redundancy

TDD - Timing Driven Design

UUT - Unit Under Test

USB - Universal System Bus

VCD - Value Change Dump

VHDL - VHSIC Hardware Description Language.

VHSIC - Very High Speed Integrated Circuit.

VLSI - Very Large Scale Integration.

V2P - Virtex – II Pro